

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS21S07A	Aug-96	9626 B2	ANAM, K.	DN613386ABA2	0.8μ NITRIDE	20 TSSOP

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-18002

<u>Electrical</u>	<u>Cum %</u>
232/0	0.0%

Sonoscan
P-18022

<u>Post Vapor Phase</u>
2/0

Infant / High Voltage Life
125°C, 7.0 V.
P-18023, P-18101

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
225/1	77/0	77/1	103 Fits
F1		F2	

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-18102

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
35/0	35/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-18103

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
74/0	74/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-18104

<u>96 Hr</u>	<u>Cum %</u>
35/0	0.0%

Failure Mode

Failure Analysis

F1: 1-Term. Resis.
F2: 1-Term. Resis.

In process
In process